

Notice of References Cited	Application/Control No. 10/801,146	Applicant(s)/Patent Under Reexamination SO, WOO-YOUNG	
	Examiner Victoria P. Whang	Art Unit 2809	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,097,037	08-2000	Joo et al.	257/55
	C	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.